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FULLY-COUPLED THERMAL-ELECTRIC-MECHANICAL MODELING OF THERMAL-ELECTRIC GENERATORS

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ABSTRACT

The development of improved power generation systems to support NASA's future deep-space exploration missions requires multi-faceted modeling to evaluate both the thermal-electric and thermal-mechanical performance of the thermal-electric generators (TEGs). To better determine generator characteristics that could meet mission needs, a fully-coupled thermal-electric-mechanical numerical model was developed in AN-SYS Mechanical and ANSYS CFX via user-defined subroutines. All pertinent thermal-electric phenomena, namely the Joule, Peltier, Thomson and Bridgman heats, were coupled to the general heat transport equation via volumetric and surface source terms. The electric potential and current density were simultaneously solved for using the Electromagnetics Model within ANSYS CFX, and said quantities evolved implicitly with the solution, as to provide the necessary boundary conditions for Maxwell's equations. Thermal expansion was modeled using a Boussinesq approximation and was coupled to the heat and thermal-electric equations via the inherent geometric dependence of thermal-electric phenomena. Deformation based on thermal expansion was handled through an iterative re-meshing routine, and was investigated under free-floating, springloaded, and constrained system configurations. Said deformation was used to determine stresses generated within each component of the TEG via ANSYS Mechanical. All thermo-physical materials were treated as temperature-dependent. Insight into the thermal-electric and thermal-mechanical performance of a unicouple, with and without interfacial compliance materials, under the influence of thermal loading was gained.

KEY WORDS: finite volume, fully-coupled, thermal-electric-mechanical, thermal deformation

INTRODUCTION

Thermal-electric devices utilize a temperature difference across semiconducting materials to create electrical power [1]. When used to generate power using the Seebeck effect, these devices are also referred to as thermal-electric generators (TEGs). The thermal conversion efficiency of such devices is too low for them to be competitive in large-scale power generation, typically ranging between 4-8% [2]. While this is the case, TEGs have several design advantages over other power generation methods – small size, solid-state operation, and long operational lifetimes – that make them useful in certain applications. Two of these applications are terrestrial waste heat recovery and extra-terrestrial power generation. For deep-space power generation applications, TEGs provide power where solar power is impractical or infeasible. In deep-space power generation applications, it is necessary for TEGs to be able to withstand thermal stresses from the heat source and

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remain functional in a thermally-deformed state.

TEG performance is dependent on the consistency of the input heat flux and subsequent temperature gradient imparted across the device, the thermal-electric (TE) materials comprising the generator, and the geometric design of the TEG itself. In space power generation, the input heat flux tends to be pseudo steady-state and well-defined, considering a radioisotope thermal-electric generator in its long-term operational environment [3]. The selection of semiconducting materials for power generation is a major factor in TEG design. Materials with a high Seebeck coefficient, α_S , low electrical resistivity, ρ , and low thermal conductivity, λ , are favorable because they produce more power for a given heat flux and tend to reach greater power densities and conversion efficiencies [4, 5]. To capture the effects of all three properties together on a material's performance, a dimensionless figure of merit, $Z\overline{T}$ is expressed in terms of the Seebeck coefficient of the *n*- and *p*-type materials, and their respective electrical resistance and thermal conductance [6], such that

$$Z\overline{T} = \frac{\alpha_S^2 \overline{T}}{R_{el} K} \tag{1}$$

It is noted that in the expression for the figure of merit, the variables within the denominator, electrical resistance, R_{el} and thermal conductance, K, take into account geometric parameters of the thermal-electric element legs [7]. Materials with a higher $Z\overline{T}$ are more capable of producing power for a given heat flux. All material properties are dependent on the temperature difference across the junctions, leading to various device designs for optimization. This includes segmented-TEGs [8–10] and multi-stage TEGs [11, 12]. The present work uses publicly-sourced temperature dependent material properties for the n- and p-type semiconductors that are not reflective of materials currently used for NASA space-power generation missions. Rather, these materials were selected to demonstrate the proposed algorithm, for both temperature-dependent thermal-electric and mechanical properties were available within the literature [13]. However, the proposed model herein is applicable to all TE materials because its primary focus is on capturing thermal-electricmechanical performance for a range of geometries and materials.

While the figure of merit is vital in understanding the thermal-electric performance of TEGs, additional material properties and device design factors must be taken into account when considering the durability of such devices. TEGs used in space power generation experience a wide range of temperature differences, sometimes in excess of 500 K [3]. Such extreme conditions can bring into question the durability of these devices, necessitating further testing and modelling of these thermo-mechanical effects. For example, Ziolkowski et al. created numerical models of TEGs using the ANSYS Parametric Design Language (APDL) [14]. Karri et al. used similar techniques to capture the effects of different constraints and leg shapes on the structural performance of TEGs [15]. Additionally, Ziabari et al. examined the effects of different design choices on the shear stresses experienced at the interfaces in TEG components [16].

To build upon prior works, an alternative coupled-model method is presented, which uses ANSYS Workbench, as well as ANSYS CFX, using the latter to quantify thermal-electric performance characteristics. The use of ANSYS CFX allows for the inclusion of all thermal-electric phenomena (including Bridgman heating) via a fully-implicit multi-physics solution algorithm and CEL expressions. The thermal-electric model implemented in ANSYS CFX provides temperature distributions within the TEG that are then used in ANSYS Mechanical to determine the resulting thermal deformation of the TEG. Upon deformation, a new mesh is created, and the ANSYS CFX model is re-solved, such that the effects of deformation on thermal-electric performance can be determined. The proposed method is implemented using temperature-dependent thermalelectric and thermo-mechanical properties. To demonstrate said method, an unsegmented single couple geometry is modelled under free, fixed, and variable elastic constraints. A contact compliance material (CCM) is then added in an attempt to decrease the maximum stresses experienced by the TE couple under thermal load. The following models are constructed using ANSYS 17.2.

METHODOLOGY

A schematic of the solution methodology is presented in Fig. 1 a), and will be elaborated upon in the following. To create deformed geometries for thermal-electric modelling in the thermo-mechanical coupled model, it is necessary to use a geometry generation scheme that allows for the TEG dimensions to be adjusted in scripting. ANSYS ICEM CFD was chosen for this purpose because it makes use of replay files to reconstruct geometries and meshes. By starting with a generalized template file for a geometry and mapping mid-solve point deformations to it, it is possible to generate geometries that account for the thermal deformation of the couple. To create the template model, a network of capture points is used to build the geometry within ICEM CFD. These capture points are shown as the black dots in Fig. 1 b). The movement of these points will be captured by the mechanical post-processor and passed back into the tool to generate a new geometry for thermal-electric modelling. The number of vertices in the model is the minimum number of capture points necessary to create a fully regenerative model, but additional points can be used along edges to capture curvature.



Fig. 1 Representation of a) a programmatic flow chart, and b) a TEG geometry with CCM and capture points.

The thermal-electric performance of the TE single-couple is captured using ANSYS CFX. The solver makes use of CEL-expressions within CFX to evaluate temperature-dependent material properties, induced thermalelectric voltage, and heats from the Peltier, Thomson, and Bridgmann effects, while Joule heating is handled implicitly by CFX's Electromagnetic Model. These expressions are linked to the leg domains as volumetric/interfacial sources for evaluation throughout. Further explanation of the calculation of heats and the CFX model is provided by Ledesma et al. on executing performance modelling within the fluids solver [17]. The same methodology for the performance modelling portion is used here.

Using a template file and the generated mesh for a given cycle, the thermal-electric performance modelling takes place within ANSYS CFX. Once the thermal-electric performance solution is completed, the body-temperature map from the CFX result is passed into ANSYS Mechanical using the one-way mapping utility provided by ANSYS Workbench. In subsequent cycles of the model, as additional thermal profiles accumulate, all are applied in a load-stepping fashion to the structural model, which always starts with the undeformed TE couple geometry. Additional constraints are then applied to the structural model, namely a fixed constraint on the cold side interconnectors (CSI) and an elastic constraint on the hot side interconnector (HSI), the stiffness of which can be adjusted. The effect of this stiffness on the resulting stresses in the TE couple will be observed using the coupled modelling technique described.

To prepare the model for simulation in the prepared framework, material properties, loads, and post-processor controls are put into ANSYS ICEM, CFX, and Mechanical template files for import into Workbench. These templates are referred to by the main macro, which is a Workbench journal executed using a run flag on startup of Workbench. To demonstrate this methodology, a generic TEG geometry is used. This geometry is not specific to any previous or current generator designs used or studied by NASA. However arbitrary

the geometry specification, it is necessary for both the thermal-electric and thermal-mechanical models. The geometry prepared is that of a TE unicouple, with two 10.00 mm long by 1.00 mm thick by 5.00 mm wide CSIs, one 15.00 mm long by 1.00 mm thick by 5.00 mm wide HSI, and two legs with cross sections of 5.00 mm by 5.00 mm and heights of 10.00 mm. When the CCM layer is applied between the HSI and the TE legs, it is of thickness 0.25 mm. A load resistance of 20.0 $\mu\Omega$ is applied, and a temperature difference of 300 K is placed across the TE couple, with the cold side set to 304 K. This temperature specification is within the range for which pertinent thermal-electrical and mechanical properties are defined, of which are available in literature [13].

As per previous grid independence studies on the given geometry, a mesh size of 50 μ m is appropriate for the thermal-electric performance model. A mesh size of 250 μ m is applied to the Mechanical model, since the captured mechanical deformation precision is limited by the number of capture points generating the geometry. Additionally, the structural mesh with the CCM layer will use a smaller sizing on the nickel material (five elements across the interface). This will allow for a more accurate examination of the layers' effect on leg stress. Finally, a convergence criterion is applied to the model: if no capture points move more than 10 μ m from iteration to iteration, the model is considered converged. This convergence criterion is applied in the Workbench journaling script. A mapping of the thermal load is shown in Figure 2.



Fig. 2 Mapping temperature to obtain thermal deformation and equivalent stress.

Material properties for the metal interconnectors, CCM layer, and n- and p-type legs are established as temperature dependent. The data is presented in Tabs. 1 and 2. Since the thermal-electric properties are input as a function of temperature into ANSYS CFX, an eighth-order polynomial fit is constructed to effectively capture the behavior of the properties in the range of 300 to 650 K [13]. The thermo-mechanical properties are added to the structural model using Workbench Engineering Data, which handles linear interpolation internally [18–20]. Some values for elastic modulus and Poisson's ratio are taken as temperature-independent in the analysis due to lack of available properties. The model is capable of using temperature-dependent values for these properties given their availability.

Structural measurements for the TE couples consist of maximum principal stress measurements taken 50 μ m from the top of the *n* and *n*-type legs. The samples taken along the path are then averaged. The maximum arch deformation is measured using a directional deformation path along the top surface of the HSI. Finally,

Coefficient	$\alpha_{S,p}$	$ ho_p$	λ_p	$\alpha_{S,n}$	$ ho_n$	λ_n
T^x	$(V K^{-1})$	$(\Omega \mathbf{m})$	$(W m^{-1} K^{-1})$	$(V K^{-1})$	(Ωm)	$(W m^{-1} K^{-1})$
0	7.6254e-05	3.5455e-04	2.1727	-3.8424e-05	8.8341e02	-7.2225
1	8.2209e-08	3.8346e-07	1.0262e-03	-9.5087e-08	6.3860e-01	6.6457e-01
2	-1.1601e-08	-2.9537e-08	-2.6517e-31	1.6046e-09	4.4790e-02	-2.3617e-03
3	1.1882e-10	3.3221e-10	-8.3596e-08	2.9312e-11	-5.1559e-04	4.1317e-06
4	-4.9366e-13	-1.5189e-12	7.4551e-10	-1.7651e-13	2.2826e-06	-3.5455e-09
5	1.0788e-15	3.6269e-15	-2.5747e-12	4.9602e-16	-5.3707e-09	1.1952e-12
6	-1.3108e-18	-4.7728e-18	4.3139e-15	-7.2655e-19	7.0825e-12	0
7	8.3947e-22	3.2849e-21	-3.5249e-18	5.4159e-22	-4.9481e-15	0
8	-2.2126e-25	-9.2555e-25	1.1295e-21	-1.6294e-25	1.4264e-18	0

 Table 1 Temperature-dependent n- and p-type thermal-electric material properties [13].

the movement of each point is captured using three user-defined results in ANSYS Mechanical - one for each axis - and the data is sent to Workbench using Design Point parameters for easy retrieval by the journal script. Measurements of thermal-electric performance are taken using ANSYS CFD-Post on the last cycle of the model.

RESULTS AND DISCUSSION

The proposed model was implemented to determine the effect of the elastic support stiffness and the inclusion of a CCM layer on the maximum principal stresses generated within the TE legs, the magnitude of the HSI deflection, and the subsequent thermal-electric performance of a single couple. To begin, the elastic support stiffness was varied between 0 (free) and 5,000 N/mm³, and the maximum principal stress in the *n* and *p*-type legs was measured, as shown in Fig. 2 a) and b), respectively. For reference, the zero-strain temperature of the TE leg is 22 degrees C. It is immediately evident that increasing the stiffness of the elastic support near-linearly increases the maximum principal stresses in both the *n* and *p*-type legs. Furthermore, the inclusion of the CCM layer near-constantly decreases the maximum principal stresses by 11% in the *n*-type leg and 12% in the *p*-type leg.



Fig. 3 Maximum principal stress in the a) *n*-type leg and b) *p*-type leg, with and without nickel CCM layer.

Next, the deflection of the HSI as a function of the elastic support loading could be examined, with results shown in Fig. 3 a). In the unconstrained case, deflection of the HSI is at a maximum, and the maximum arch deformation occurs at the middle of the HSI as it deflects upward, as shown in Fig. 3 b). When the elastic constraint's stiffness is increased, however, the middle of the interconnector undergoes deflection in the opposite direction, as evidenced in Fig. 3 b), which will result in a substantial stress in the region of high

	Interconnector			CCM Layer		
Temperature	E_{int}	\mathbf{v}_{int}	$\alpha_{T,int}$	E_{ccm}	\mathbf{v}_{ccm}	$\alpha_{T,ccm}$
(K)	(GPa)	(-)	10^{-6} (-)	(GPa)	(-)	10^{-6} (-)
200	133	0.341	15.0	-	-	11.0
250	-	-	16.0	-	-	12.6
300	-	-	16.6	-	-	12.6
350	-	-	17.0	-	-	13.0
400	120	0.346	17.5	-	-	13.4
450	-	-	17.7	-	-	13.9
500	-	-	18.0	-	-	14.3
550	-	-	18.4	-	-	14.5
600	109	0.352	18.7	180	0.34	14.8
	<i>p</i> -type		<i>n</i> -type			
Temperature	E_p	\mathbf{v}_p	$\alpha_{T,p}$	E_n	\mathbf{v}_n	$\alpha_{T,n}$
(K)	(GPa)	(-)	10^{-6} (-)	(GPa)	(-)	10^{-6} (-)
341	436	0.29	11.3	436	0.29	11.2
391	-	-	11.5	-	-	11.4
441	-	-	11.7	-	-	11.8
492	-	-	11.9	-	-	12.0
542	-	-	12.1	-	-	12.2
593	-	-	12.4	-	-	12.3
634	-	-	12.6	-	-	12.5

 Table 2 Temperature-dependent CCM layer, interconnector, n- and p-type thermo-mechanical properties [13].

deformation gradients. There is a clear relation between HSI deformation as shown in Fig. 3 b) and maximum principal stresses within the TE legs as shown in Fig. 3 a). As the HSI is unable to deform upwards, i.e. there is an increase in the elastic support stiffness, the principal stresses within the TE legs increase. Furthermore, with a greater temperature difference imposed across the generator, the deformation of the HSI and subsequent imparted stresses within the TEG will increase. Thus, it is imperative to incorporate compliance into the HSI, especially at higher-temperature scenarios.

Additionally, the effect of mechanical deformation on thermal-electric performance was able to be determined. For a TED allowed to freely expand on the hot side interconnector, the TE leg lengths increase by only 0.2% for a thermal load of 300 K, and the generated electric current decreases by about 1%. This is due to the increase of electrical resistance of the TE legs due to the slight increase in length. With an elastic constraint of 5,000 N/mm³, however, the generated current decreases by less than a tenth of a percent. It is expected that applying a larger thermal load on the legs (500 K or more) will cause a greater change in this value for current.

Considering all scenarios under which the proposed model was tested, said model converged in two cycles given the specified convergence criteria. This rapid convergence is attributable to fact that the thermal characteristics of the TEG change minimally after the first cycle of the model. That is to say, without significant deformation, there will be insignificant changes to the thermal-electric material properties, namely electrical resistance and thermal conductance of the legs, due to the treatment of the electrical resistivity and thermal conductivity via a Boussinesq approximation. Additionally, the imparted temperature difference of 300 K is relatively small in terms of eliciting thermal deformation. It is expected that using a higher temperature difference (500 to 1,000 K) will require more cycles to reach the specified convergence criteria. With that being said, the proposed model allows for the rapid thermal-electric-mechanical coupled modeling of TEGs, such that the effects of thermal deformation on thermal-electric performance can be evaluated.



Fig. 4 Maximum a) upward deflection of the HSI with and without a CCM layer and b) path deflection of the HSI on the no-CCM model, with and without a stiff elastic constraint.

CONCLUSIONS

The proposed fully-coupled thermal-electric-mechanical model of TE couples, although more computationally expensive than segregated thermal-electric and thermal-mechanical models due to the iterative re-meshing scheme, has the ability to simultaneously quantify the effects of thermal-induced deformations on the mechanical behavior and thermal-electric performance on device performance. Specifically, a TE couple with a free-floating HSI experiences the least amount of principal stresses generated within the TE materials, sees the greatest deflection of the HSI, as well as experiences the greatest change of thermal-electric performance. As the stiffness of the elastic support increases, the principal stresses with the TE materials increase, the deformation of the HSI decreases, and the thermal-electric performance changes substantially decrease. It is also found that the inclusion of a CCM layer substantially decreases the maximum principal stresses within the TE couple as well as the deformation of the HSI. The proposed model can rapidly evaluate the suitability of various TE and CCM materials, as well as TEG designs, for a diverse set of TEG applications.

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Variables Elastic modulus (GPa) R_{el} Electrical resistance (Ω) Thermal conductance (WK^{-1}) TTemperature (K) ZTDimensionless figure of merit *n*-type (-) *p*-type **Subscripts and Superscripts** Cold side ccmCCM Layer Interconnector *p*-type pOrder of coefficient Hot side x*n*-type **Greek Letters** Seebeck coefficient (VK^{-1}) Poisson's Ratio γ (-) Coefficient of thermal expansion (-) Electrical resistivity (Ωm) ρ $(Wm^{-1}K^{-1})$ Thermal conductivity

NOMENCLATURE

Acronyms

CCM	Contact compliance material	TE	thermal-electric
CSI	Cold side interconnector	TED	thermal-electric device
HSI	Hot side interconnector	TEG	thermal-electric generator

E

K

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n

 α_{S}

 α_T

λ

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